

Search Notes

Application/Control No.

10/801,872

Examiner

Benny Q. Tieu

Applicant(s)/Patent under
Reexamination

MEEK ET AL.

Art Unit

2614

SEARCHED

Class	Subclass	Date	Examiner
379	211.01 211.02 201.01 196 127.01	7/22/2005	BQT
	142.05		
	93.03		
	142.05		
	114.25		
Updated	Search	12/7/2005	BQT
Updated	Search	5/13/2006	BQT
Updated	Search	10/11/2006	BQT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	7/22/2005	BQT